Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/530,532	YAMADA, RITSUKO	
Examiner	Art Unit	
David Buttner	1712	

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
inventor search	3/2/2007	DB	
east	3/2/2007	DB	
west	3/2/2007	DB	
west	3/2/2007	DB	
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